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| Notice of References Cited | Application/Control No. 10/780,218 | Applicant(s)/Patent Under Reexamination LIANG ET AL. | |
| | Examiner Stephen E. Jones | Art Unit 2817 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------------|----------------|
| | A | US-6,374,094 | 04-2002 | Zappala, Christopher F. | 455/188.1 |
| | B | US-3,656,162 | 04-1972 | Mee, Thomas Francis | 370/339 |
| | C | US-5,276,914 | 01-1994 | Ishizuka et al. | 455/83 |
| | D | US-6,096,127 | 08-2000 | Dimos et al. | 117/9 |
| | E | US-5,896,073 | 04-1999 | Miyazaki et al. | 333/204 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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